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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/790,986	EGUCHI, TAKEO	
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Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC)
	DATE	EXMR
EAST limited text search	3/6/2007	CD
Inventor Search	3/6/2007	CD
HTML at Google	3/6/2007	CD
IEEE Explorer	3/6/2007	CD
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